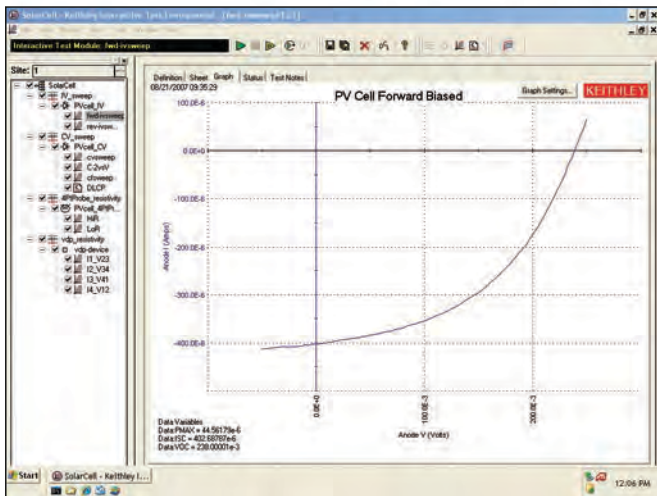


Simplify Your Solar Cell Testing with Keithley's Precision Measurement Solutions



Keithley's solutions for solar cell I-V and C-V characterization provide the most accurate measurements available without the hassles of integrating separate instruments or writing complicated programs.

Electrical characterization of a variety of solar cell (Photovoltaic) technologies, including:

- Mono Crystalline Si
- Poly Crystalline Si
- Amorphous Si
- CIGS
- CdTe
- Polymer Organic

Measurement of key parameters including:

- Open circuit voltage (V_{oc})
- Short circuit current (I_{sc})
- Maximum power output (P_{max})
- Voltage at P_{max} (V_{max})
- Fill factor (ff)
- Series resistance (R_s)
- Shunt resistance (R_{sh})
- Conversion efficiency (η)
- Doping density (N)
- Cell resistivity
- Defect density

MODEL 4200-SCS SEMICONDUCTOR CHARACTERIZATION SYSTEM

- Fully integrated I-V and C-V turn key solution with intuitive graphical user interface
- Built-in libraries for extracting key cell parameters, and advanced analytical and formulation tools

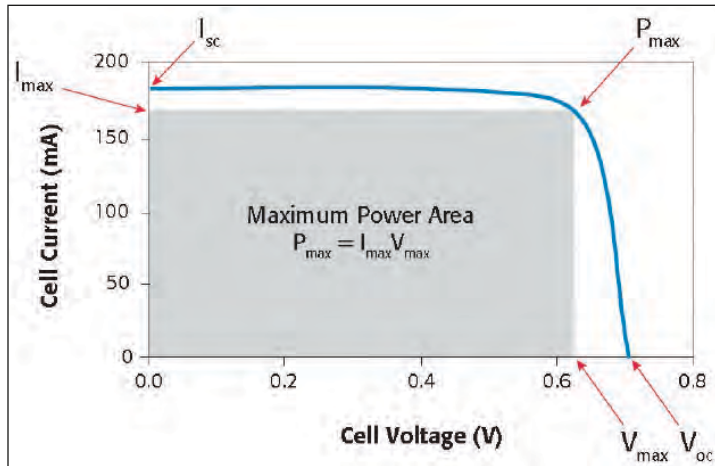
SERIES 2400 OR 2600A SOURCEMETER® INSTRUMENTS

- 4-quadrant design provides both source and sink capability for complete I-V
- All-in-one solution for I-V characterization with the combined functionality of a precision power supply, high precision DMM, and electronic load

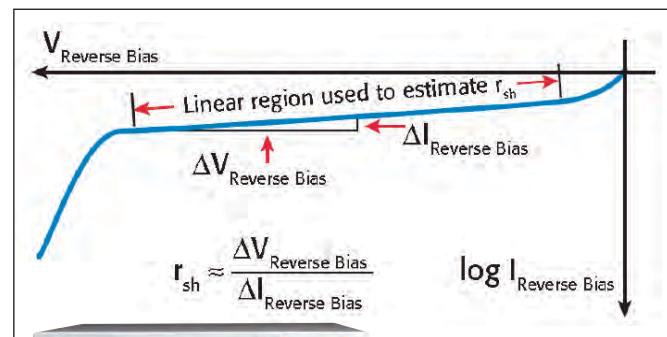
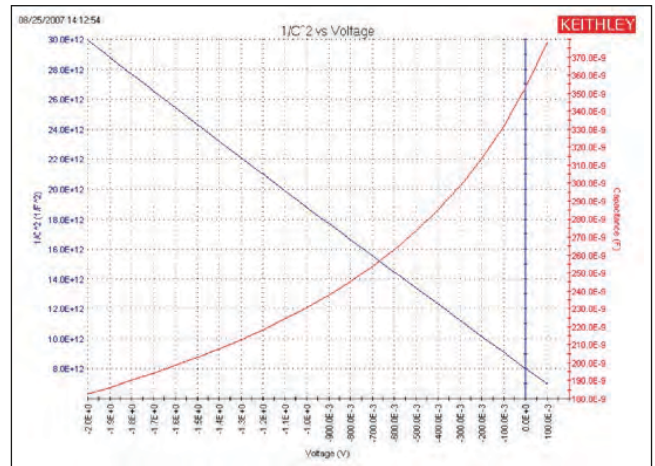
KEY SOLAR CELL PARAMETERS AND MEASUREMENT TECHNIQUES

These measurements were made using Keithley's solutions for solar cell testing.

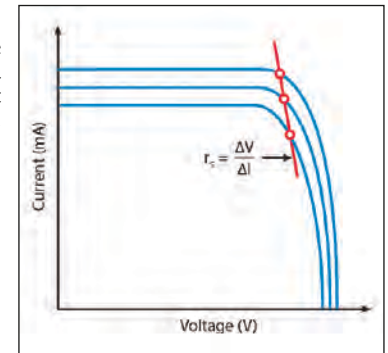
Doping Density (N) of a Crystalline-Si solar cell can be derived from capacitance-voltage sweep. (This feature is available on Model 4200-SCS with C-V option.)



Typical forward biased I-V characteristic of a solar cell.



Series resistance (R_s) can be determined from a forward I-V sweep of a solar cell at multiple light intensities.



Shunt resistance of a solar cell can be estimated from a reverse bias I-V sweep.



PARAMETER ANALYZER	SOURCE AND MEASURE INSTRUMENTS	
Model 4200-SCS Semiconductor Characterization System	Model 2602A SourceMeter Instrument	Model 2440 or 2425 SourceMeter Instruments
<ul style="list-style-type: none"> 4-quadrant operation (source/sink) 1A at 20V 100mA at 200V Capacitance-Voltage (C-V) option Turn key solution with built-in software for complete data analysis and cell parameter calculations Combine with Model 707A Switch Matrix for multi-cell testing. 	<ul style="list-style-type: none"> 4-quadrant operation (source/sink) Dual channel 3A at 6V 10A at 20V pulse 1A at 20V Built-in TSP® Express software for quick and easy I-V test ACS Basic Edition software option with preconfigured solar project Combine with Series 3700 System Switch and Multimeter for multi-cell testing. 	<ul style="list-style-type: none"> 4-quadrant operation (source/sink) 5A at 10V (Model 2440) 3A at 20V (Model 2425) 1A at 100V (Model 2425) Built-in sweep functions for convenient I-V profiling 6 different models available for a wide range of I-V requirements Combine with Models 7001 or 7002 Switch Mainframes for multi-cell testing.

For More Information:



Leading the way in test and measurement

Vicom Australia

1064 Centre Rd
Oakleigh South Vic
3167 Australia 1300
360 251
info@vicom.com.au
www.vicom.com.au

Vicom New Zealand

Grd Floor, 60 Grafton Road
Auckland 1010
New Zealand
+64 9 379 4596
info@vicom.co.nz
www.vicom.co.nz



© Copyright 2009 Keithley Instruments, Inc.

Specifications are subject to change without notice.

All Keithley trademarks and trade names are the property of Keithley Instruments, Inc. All other trademarks and trade names are the property of their respective companies.